

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Eiichi IDE, et al.

Serial No.:

Group Art Unit:

Filed: December 27, 2000

Examiner:

For: THREE-DIMENSIONAL SHAPE MEASURING SYSTEM



INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, DC 20231

Dear Sir:

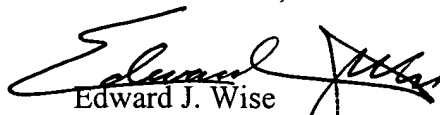
In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English reference is accompanied by an English abstract.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION							
			ATTY. DOCKET NO. 48864-034		SERIAL NO.		
(PTO-1449)			APPLICANT Eiichi IDE, et al.				
			FILING DATE December 27, 2000	GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
	4,559,597	12/17/85	Mullani				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	6-185993	7/8/94	Japan (with English abstract)				
	7-327977	12/19/95	Japan (with English abstract)				
	8-336151	12/17/96	Japan (with English abstract)				
	9-204158	8/5/97	Japan (with English abstract)				
	2000-148649	5/30/00	Japan (with English abstract)				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.